

Notice of References Cited	Application/Control No. 10/003,340	Applicant(s)/Patent Under Reexamination LITTLE, JAMES M.	
	Examiner Lawrence B Williams	Art Unit 2634	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,736,163	04-1988	Berkhout et al.	327/58
	B	US-4,700,365	10-1987	Casey, Robert F.	375/317
	C	US-6,026,773 A	02-2000	LaBelle, James L.	123/179.3
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0122504 A1	09-2002	Payne et al.	375/317
	B	US-4,823,360	04-1989	Tremblay et al.	375/214
	C	US-5,832,039 A	11-1998	Rijns, Johannes J. F.	375/317
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP001148682A2	10-2001		Oren, Eliezer	H04L 25/06
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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